

Figure S1. Atomic force microscopy (AFM) images of the ZnO (a, d), SnO₂ (b, e) and SnO₂/ZnO (c, f) films. And the root-mean-square (RMS) roughness of the ZnO, SnO₂ and SnO₂/ZnO films are 2.95 nm, 1.76 nm and 1.94 nm, respectively.

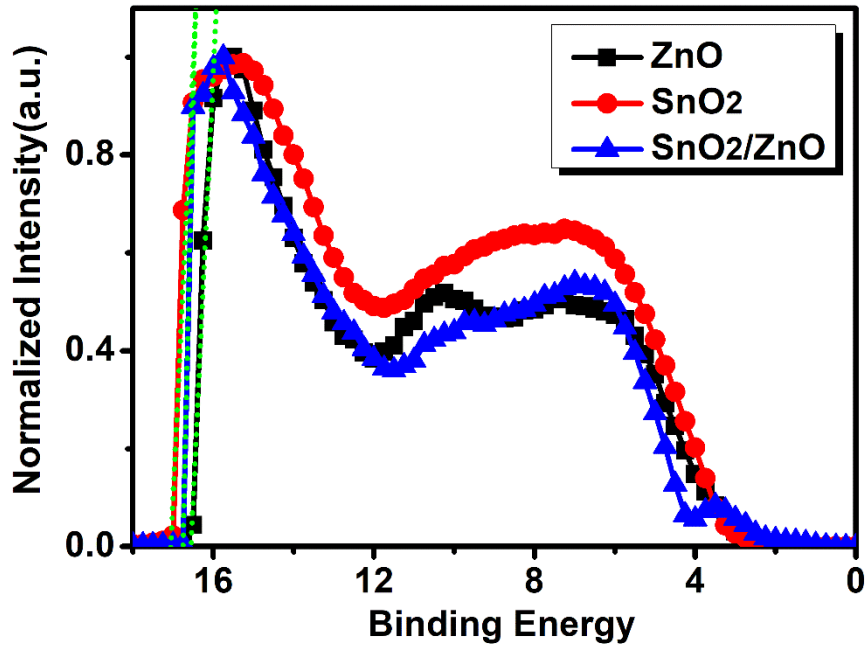


Figure S2. Ultraviolet photoelectron spectrometry (UPS) spectra of the ZnO, SnO₂ and SnO₂/ZnO films.

Table S1. The secondary electron cutoff and work function derived from UPS spectra.

	Secondary electron cutoff (eV)	Work function (eV)
ZnO	16.65	4.57
SnO₂	17.19	4.03
SnO₂/ZnO	16.96	4.26